

About robustness of test patterns regarding multiple faults

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Motivation-driven learning processes at the example of embedded systems

Hollstein, Thomas; Reinsalu, Uljana; Leier, Mairo 10th European Workshop on Microelectronics Education : EWME 2014 : May 14-16, 2014, Tallinn, Estonia 2014 / p. 3-6 : ill

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Teaching embedded systems as a part of a computer engineering curricula

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